

On the Recoverability of Persistent Memory Systems

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Motivation

 Persistent Memory (PM) technologies offers durability similar to flash memory with latencies comparable to DRAM

	DRAM	PCM	RRAM	MRAM	SSD	HDD
Read Latency	60 ns	50 ns	100 ns	20 ns	25 μs	10 ms
Write Latency	60 ns	150 ns	100 ns	20 ns	300 μs	10 ms
Addressability	Byte	Byte	Byte	Byte	Block	Block
Volatile	Yes	No	No	No	No	No
Energy/bit access	2 pJ	2 pJ	100 pJ	0.02 pJ	10 nJ	0.1 J
Endurance	>10 ¹⁶	10 ¹⁰	10 ⁸	10 ¹⁵	10 ⁵	>10 ¹⁶

Table 1: Characteristics of various memory/storage technologies

- Recent research have optimized different layers/components of PM-aware applications
 - NV-Heaps, Mnemosyne, DudeTM, NOVA, etc.
- PM-aware applications achieve high performance while maintaining high recoverability
- But the evaluation of these applications is unbalanced

Various benchmarks demonstrate performance gain but provide *little measurement* of recoverability guarantee

Methodology

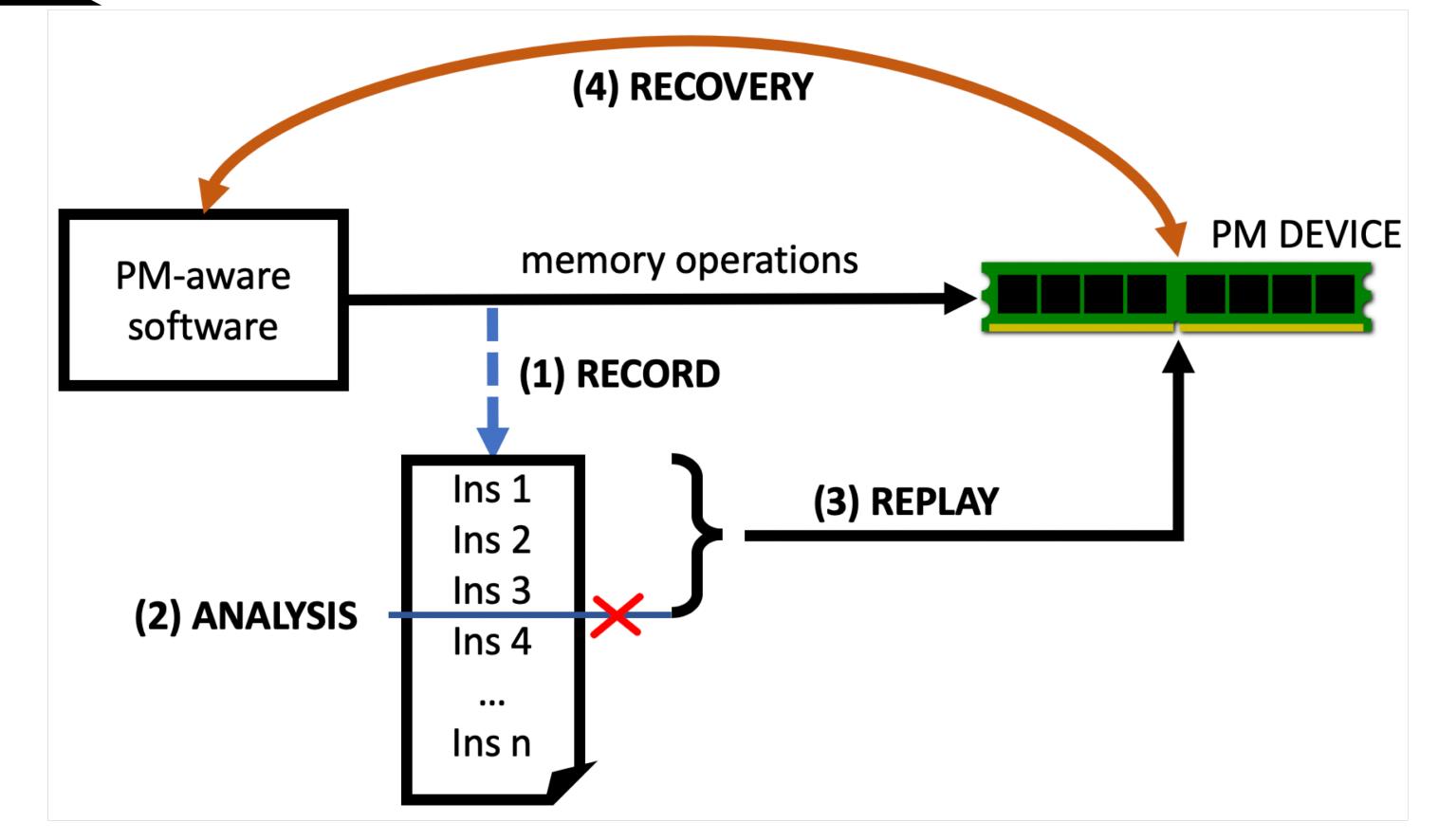


Figure 1: A block diagram depicting the methodology

- A fault injection framework to systematically test recoverability
- Four steps:
 - *Record:* instrument target system to capture memory operations, as well as recovery instructions (*clflush*)
 - Analysis: identify most vulnerable points for fault injection
 - Replay: replay target system up to a specific execution point
- *Recovery:* invoke recovery component of target system and examine recoverability

Two types of faults based on the granularity: Macro and Micro

Macro (M)	Micro (m)		
Faults that occur at the	Faults that occur during		
boundaries of PM lib functions	PM lib functions		
Ex.: after <i>pmalloc</i> finishes	Ex.: inside <i>pmalloc</i>		
Coarse-grained fault to test	Fine-grained fault to test PM		
application-level recovery	management thoroughly		
protocol			

Table 2: Two types of faults

| Preliminary Results

- Used N-Store as one case study
- Used Intel's PIN to record memory instructions and identify boundaries of functions (ex.: *pmalloc*)
- Save memory-mapped file at each dynamic fault point and attempt to restore
- Injected 4 faults: Macro-1, Macro-2, Micro-1 and Micro-2
- N-Store successfully recovers from Macro-1, Macro-2 & Micro-1
- Segmentation fault occurs when recovering from Micro-2
 - PM library was unable to restore PM to clean state

Fault Type	Description	Level	
Macro-1	after a transaction commit	Application	
Macro-2	within a transaction	Application	
Micro-1	in <i>pmalloc</i> (b/w two <i>clflush</i>)	Library	
Micro-2	in <i>pmalloc</i> (before any <i>clflush</i>)	Library	

Table 3: Description for each Macro and Micro faults

Fault Type	Target Component	Recovery Successful?
Macro-1	Undo log of N-Store	Yes
Macro-2	Undo log of N-Store	Yes
Micro-1	pmemlib	Yes
Micro-2	pmemlib	No

Table 4: Experimental results from fault injection

| Future Work

- Investigate the root cause for the segmentation fault
- Identify more vulnerable points in the memory operations
- Extend the prototype to automatically identify the boundaries of PM functions
- Reduce the overhead of memory tracing
- Test more PM applications for recoverability